

In the Specification

Please change the title to "Test Method For Semiconductor Components Using Conductive Polymer Contact System".

On page 2, line 1, add the following:

Cross Reference To Related Applications

This application is a division of Serial No. 10/037,607 filed 01/07/2002, which is a division of Serial No. 09/652,826 filed 08/31/2000, Patent No. 6,462,568 B1.